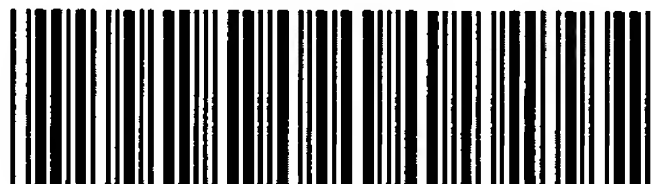


Search Notes



Application/Control No.

10/026,618

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

LEE ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	316	10/19/06	ELH
↑	326		
	327		
	340		
	341		
	327		
	344		
↓	345		
375	150		
379	350	10/2/06	ELH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
2611	10/19/06	ELH